

What is claimed is

1. An oxidation decomposition element analyzer comprising,
a sample supply portion for supplying a sample to be analyzed,
an oxidation reagent supply portion for supplying an oxidation
5 reagent,

an oxidation reaction portion connected to the sample supply
portion and the oxidation reagent supply portion to receive the
sample and the oxidizing reagent for reaction,

an analyzing portion connected to the oxidation reaction
portion for analyzing an oxidized component to be measured to
10 obtain a concentration of the component, and

a controlling portion electrically connected to the sample
supply portion, oxidation reagent supply portion and oxidation
reaction portion for controlling operations of supplying the sample
and the oxidation reagent to the oxidation reaction portion, said
controlling portion controlling such that the oxidation reagent is
supplied to the oxidization reaction portion before the sample is
supplied thereto and the sample is supplied after elapse of time
during which impurities contained in the oxidation reagent are
20 removed through an oxidization decomposition at the oxidization
reaction portion.

2. An oxidation decomposition element analyzer according to claim
1, further comprising a carrier gas supply portion for supplying a
25 carrier gas to the oxidation reaction portion, and an inorganic
carbon sparger connected to the analyzing portion for measuring
inorganic carbon concentration.

3. An oxidation decomposition element analyzer according to claim 2, wherein the oxidation reaction portion includes an ultraviolet lamp so that organic materials contained in the sample injected therein are entirely oxidized by the oxidation reagent and ultraviolet rays to be converted into carbon dioxide.

4. An oxidation decomposition element analyzer according to claim 3, wherein said analyzing portion is an infrared gas analyzer.

5. A method of analyzing a sample, comprising:

supplying an oxidation reagent for analyzing a subject to an oxidation reaction portion,

subjecting impurities contained in the oxidation reagent to oxidization decomposition at the oxidation reaction portion,

removing the impurities subjected to the oxidization decomposition from the oxidation reaction portion,

providing a sample to the oxidation reaction portion and reacting with the oxidation reagent without the impurities, and

analyzing a gas obtained from the oxidation reaction portion by an analyzing portion.

6. A method of analyzing a sample according to claim 5, wherein in the analyzing portion, a measured peak is subjected to an area calculation and compared with a corrected result which has been obtained beforehand to thereby calculate a concentration thereof.

7. A method of analyzing a sample according to claim 6, wherein in the oxidization reaction, a carbon dioxide gas is generated and is

carried to the analyzing portion by a carrier gas flowing through the oxidization reaction portion to thereby measure a concentration thereof.